What is claimed is:

- 1. An integrated package comprising:
 - a first wafer having a first surface;
 - a second wafer having a first surface bonded at a first perimeter to the first surface of the first wafer; and
 - a recess formed in the first surface of the first wafer in a second perimeter situated within the first perimeter.
- 2. The package of claim 1, further comprising a first bump pattern in the first surface of the first wafer within the second perimeter.
- 3. The package of claim 2, further comprising a second bump pattern on a second surface of the first wafer.
- 4. The package of claim 3, further comprising a seal between the first and second wafers at the first perimeter.
- 5. The package of claim 4, wherein the seal comprises:
 a spacer material; and

- · a layer of malleable material.
- 6. The package of claim 5, wherein the seal further comprises a layer of bondable material.
- 7. The package of claim 6, further comprising structural supports in the recess of the first wafer.
- 8. The package of claim 7, further comprising at least one pumpout opening in the first wafer.
- 9. The package of claim 8, wherein the first and second wafers comprise silicon.
- 10. A method for making an integrated package, comprising: providing a first wafer;
 - making a recess at a first perimeter in a first surface of the first wafer; and
 - bonding a second wafer to the first wafer with a seal formed at a second perimeter outside the first perimeter.

- 11. The method of claim 10, further comprising forming a first bump pattern on the first surface of the first wafer prior to the bonding of the second and first wafers.
- 12. The method of claim 11, further comprising forming at least one opening through the first wafer prior to the bonding of the second and first wafers.
- 13. The method of claim 12, further comprising baking out the first and second wafers after the bonding of the first and second wafers.
- 14. The method of claim 13, wherein the baking out the first and second wafers is done within a substantial vacuum.
- 15. The method of claim 14, further comprising sealing the at least one opening through the first wafer within the substantial vacuum.
- 16. The method of claim 15, further comprising forming a second bump pattern on a second surface of the first wafer.

- 17. The method of claim 16, wherein the first and second bump patterns have an anti-reflective characteristic.
- 18. The method of claim 17, wherein the seal comprises:

 a spacer material; and

 a malleable layer.
- 19. The method of claim 18, wherein: the seal further comprises a layer of gold-like material; and the malleable layer comprises a solder-like material.
- 20. A means for integral packaging, comprising: means for providing a first wafer having a recess about a first perimeter in a first surface of the first wafer; and means for providing a second wafer bonded to the first wafer.
- 21. The means of claim 20, wherein the recess is hermetically sealed from an environment external to the

first and second wafers.

- 22. The means of claim 21, wherein the first surface of the first wafer has a first bump pattern within the first perimeter.
- 23. The means of claim 22, wherein the first and second wafers comprise a bonding seal along a second perimeter outside of the first perimeter.
- 24. The means of claim 23, wherein the bonding seal comprises:
 - a spacer material; and
 - a malleable layer.
- 25. The means of claim 24, wherein:
 - a second surface of the first wafer has a second bump pattern; and
 - the first and second bump patterns are antireflective.
- 26. An integral package comprising:

- a first wafer comprising:
 - a seal along a first perimeter on a first surface of the first wafer; and
 - a trench in the first surface of the first wafer along a second perimeter within the first perimeter; and
- a second wafer having a first surface bonded to the second wafer along the seal.
- 27. The package of claim 26, wherein the first wafer further comprises an anti-reflective pattern on the first surface.
- 28. The package of claim 27, wherein the first wafer further comprises at least one vent hole and vent hole seal.
- 29. The package of claim 28, wherein the seal comprises a spacer material.
- 30. The package of claim 29, wherein the first wafer further comprises an anti-reflective pattern on a second

surface.